## Measurement of the charged pion mass using X-ray spectroscopy of exotic atoms

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KΒ

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## Pion production and first mass measurements





[1] E. Gardner and C. Lattes, Science 107, 270-271 (1948)





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### New pionic atom spectroscopy and pion decay measurements

## Pionic spectroscopy and pion decay Dischungszentrum Pionic spectroscopy and pion decay measurements



### New pionic atom spectroscopy and pion decay measurements



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## PAUL SCHERRER INSTITUT PIONIC Spectroscopy and pion decay measurements



### New pionic atom spectroscopy and pion decay measurements



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## Pionic atoms formation and atomic cascade









### Pion mass measurement problems







## New measurement of the pion mass



**JULICH Present official value and new proposal** 





Average between :

- Jeckelmann 1994 solution B (solid target)
- Lenz 1998 (gaseous target)

Particle Data Group. Chinese Phys. C 38, 090001 (2014)

### PSI proposal R-97-02

NEW PRECISION DETERMINATION OF THE CHARGED PION MASS

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- Gaseous target
- $\rightarrow$  no remaining el. contamination
- Muonic Oxygen transition as calibration
- $\rightarrow$  high accuracy of the energy reference





## Pion beam production



### Production at the Paul Scherrer Institut (Villigen, Switzerland)

- Proton beam :E<sub>kin</sub>=590 MeV, I=1.9 mA
- Graphite target
- 10<sup>8</sup> pions/s,  $E_{kin}$ =110 MeV



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## Pionic and muonic atoms production





N. of  $\pi$ N atoms = 10 x N. of  $\mu$ O atoms



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# Pionic atoms formation and atomic cascade with N<sub>2</sub> gaseous target









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### Strong interaction effects minimized







## Set-up at PSI





26 January 2012



## Diffraction crystal and position sensitive detector



### Si(110) crystal [1]



Radius of curvature: ~ 3 m Diameter: 10 cm Thickness: 290 µm Support: polished quartz lens

Produced by Zeiss (Oberkochen, Germany)

D.S. Covita *et al.*, Rev. Sci. Instum. **79**, 033102-3 (2008)
 N. Nelms *et al.*, Nucl. Instrum. Methods A **484**, 419 (2002)
 P. Indelicato *et al.*, Rev. Sci. Instum. **77**, 043107 (2006)

2 × 3 X-ray CCD array with frame buffer [2,3]

pixel size  $40 \ \mu m \times 40 \ \mu m$  $600 \times 600$  pixels per chip frame transfer  $\approx 10 \ ms$ 

data processing 2.4 s operates at - 100°C

 $\Delta E \approx 150 \text{ eV}$  @ 4 keV Efficiency  $\approx 90\%$ 



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## Data acquisition and pre-analysis



### ... after 5 weeks of data collection ...

6000 counts in each line Spectrometer transmission:  $5x10^{-8}$ Stability of the set-up monitored by 8 keV Cu K $\alpha$ fluorescence line (fourth order reflection)





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## 5g-4f transitions in $\pi N$ and $\mu O$







## 5g-4f transitions in $\pi N$ and $\mu O$







## Lines profiles and positions



[5] D.E. Gotta et al., Spectrochim. Acta, Part B 120, 9 (2016)



Eventual position of the satellite line

From the line position to the pion mass

### From the spatial diff. to the angular position diff.

 $\Delta\Theta = -2\arctan\left(\frac{\Delta x}{2D}\right)$ 

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**Statistical uncertainty**: line positions: ± 0.045 pixel

Systematics uncertainty: <u>crystal-detector distance</u>, CCD positions and pixel size [1], line modeling, spectrometer response function [2-6], Bragg law corrections [7], ...





Bragg law

[1] P. Indelicato *et al.*, Rev. Sci. Instum. 77, 043107 (2006)
[5] M. Theisen, Diplomarbeit thesis, University of Aachen (2013)
[2] D.F. Anagnostopoulos *et al.*, Nucl. Instrum. Methods B 205, 9 (2003)
[6] D.E. Gotta *et al.*, Spectrochim. Acta, Part B 120, 9 (2016)
[7] M.T., Ph.D. thesis Pierre et Marie Curie University (2005)
[4] D.S. Covita, Ph.D. thesis University of Coimbra (2008)

From the line position to the pion mass From the spatial diff. to the angular position diff. 400  $\Delta\Theta = -2\arctan\left(\frac{\Delta x}{2D}\right)$ μΟ πN 25 mm 100 Λх 1000 From the angular position diff. to the transition energy pixel  $E_{\pi N} = E_{\mu O} \overline{\cos\Delta\Theta - \frac{\sqrt{1 - [hc/(2dE_{\mu O})]^2}}{hc/(2dE_{\mu O})}}\sin\Delta\Theta$  $\left|\frac{hc}{E} = 2d\sin\Theta_B\right|$ where Bragg law where  $E_{\mu O} = f_{\text{QED}}_{\text{Dirac}}(m_{\mu}) = \tilde{m}_{\mu}c^{2} \frac{(Z\alpha)^{2}}{2} \left(\frac{1}{n_{f}^{2}} - \frac{1}{n_{i}^{2}}\right) + \mathcal{O}_{\text{QED}}_{\text{Dirac}}(Z^{4}\alpha^{4})$  $E(5g-4f \pi N) = 4055.397 \pm 0.005 eV$ Crystal spacing, conversion constant,

[3] J. P. Santos et al., Phys. Rev. A 71 (2005) 032501

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QED calculation (for µO) [1-3], ....

<sup>[1]</sup> P. Indelicato, private comunication

<sup>[2]</sup> J. Desclaux et al., Computational Approaches of Relativistic Models in Quantum Chemistry, vol. 10, Elsevier, 2003.

From the line position to the pion mass ÜLICH From the spatial diff. to the angular position diff. 400  $\Delta\Theta = -2\arctan\left(\frac{\Delta x}{2D}\right)$ struo 200 25 mm

From the angular position diff. to the transition energy

$$E_{\pi N} = E_{\mu O} \frac{1}{\cos \Delta \Theta - \frac{\sqrt{1 - [hc/(2dE_{\mu O})]^2}}{hc/(2dE_{\mu O})}} \sin \Delta \Theta$$
  
where  
$$E_{\mu O} = f_{\text{QED}}(m_{\mu}) = \tilde{m}_{\mu} c^2 \frac{(Z\alpha)^2}{2} \left(\frac{1}{n_f^2} - \frac{1}{n_i^2}\right) + \mathcal{O}_{\text{QED}}(Z^4 \alpha^4)$$

$$\frac{hc}{E} = 2d\sin\Theta_B$$
Bragg law

QED calculation (for  $\pi N$ ) [1], ....

Λx

pixel

100

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$$m_{\pi} = f_{\text{QED}}^{-1}(E_{\pi N})$$
<sub>Klein-Gordon</sub>

[1] M. Trassinelli et al., Phys. Rev. A 76, 012510(2007)



πN

1000



## $\pi N$ transition energy calculations

### The Klein-Gordon equation

$$\left(\frac{1}{c^2}[E+eV_0(r)]^2+\hbar^2\nabla^2-m^2c^2-W(\mathbf{r})\right)\varphi(\mathbf{r})=0$$

 $5 \rightarrow 4 \pi N$  QED transition energies details (in eV) [1]

$$E_{(0)}^{nl} = \frac{mc^2}{\sqrt{1 + \frac{(Z\alpha)^2}{\left[n - l - 1/2 + \sqrt{(l + 1/2)^2 - (Z\alpha)^2}\right]^2}}}$$

for Coulomb potential with point-like and infinite mass nucleus

	5 <i>g</i> -4 <i>f</i>	5 <i>f</i> -4 <i>d</i>
Coulomb	4054.1180	4054.7189
Finite size	0.0000	0.0000
Self-energy	-0.0001	-0.0003
Vacuum polarization (Uehling)	1.2485	2.9470
Vacuum polarization (Wichman-Kroll)	-0.0007	-0.0010
Vacuum polarization (loop after loop)	0.0008	0.0038
Vacuum polarization (Källén-Sabry)	0.0116	0.0225
Relativistic recoil	0.0028	0.0028
HFS shift	-0.0008	-0.0023
Total	4055.3801	4057.6914
Error	±0.0011	±0.0011
Strong interaction effects:	44 μeV	7 meV
	[1] M. T	rassinelli <i>et al.</i> , P

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## List of systematic effects

type of uncertainty	μO / arcsec	πN / arcsec	total / arcsec	uncertainty / ppb
index of refraction shift silicon lattice constant	13.22	12.94	- 0.28	$\begin{array}{c} \pm 20 \\ \pm 2 \end{array}$
bending correction penetration depth correction	14.01 -0.07	13.71 -0.07	0.30 0	$\begin{array}{c} \pm 20 \\ \pm 4 \end{array}$
focal length				$\pm 670$
pixel distance				± 120
alignment of detector normal detector height offset	Total u	ncertainty:	1.3x10 <sup>-6</sup>	+ 0 - 30 + 0
shape of target window shape of reflection individual curvature correction temperature correction	Statistic System	cal: natics:	0.8x10 <sup>-6</sup> ~1x10 <sup>-6</sup>	$^{-35}$ $\pm 100$ $\pm 225$ $\pm 150$ $\pm 30$
response function and Doppler broadening line pattern modelling fit interval				$+290 - 350 + 190 - 290 \pm 15$
QED energy conversion constant $hc$ $4f$ strong interaction $45 \mu \text{eV}$ $5g$ strong interaction $0.2 \mu \text{eV}$ K electron screening		0.003 0.000	-0.003 0.000	$\pm 350 \\ \pm 2 \\ \pm 10 \\ \pm 0 \\ \pm 0$
total systematic error statistical error				+ 950 - 1000 ± 820

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## The new measurement of the pion mass





Particle data group [1]: 139.57018 ± 0.00035 MeV/c<sup>2</sup> → 2.5x10<sup>-6</sup> accuracy

Our work [2]: 139.57077 ± 0.00018 MeV/c<sup>2</sup> → **1.3x10**<sup>-6</sup> accuracy

- No effect of eventual remaining K-shell electrons (<10<sup>-9</sup>)
- High accuracy calibration line (0.25x10<sup>-6</sup> from theory calc.)

[1] Particle Data Group. Chinese Phys. C 38, 090001 (2014)
 [2] M. Trassinelli et al., arXiv:1605.03300 (2016)



## Additional results





 $m_{\nu_{\mu}} \in [100, 244] \ keV/c^2$ (90% c.l.)

in disagreement with astrophysical boundaries (WMAP and Planck) <0.6–2.3 eV and <sup>3</sup>H decay + v oscillations











## Additional results



Muonic neutrino mass Pion decay measurement  $p_{\mu}$  = 29.792006 ± 0.00011 MeV/c

Pion mass measurement  $m_{\pi}$  = 139.57077 ± 0.00018 MeV/c<sup>2</sup>  $n_{\nu_{\mu}} \in [100, 244] \ keV/c^2$ 

0.4% accuracy test

(90% c.l.)

Klein-Gordon equation test

Relativistic quantum mechanic equation for spin-0 particles (+ QED corrections)

 $\Delta E_{theory}$  = 2.318 ± 0.007 eV error due to the strong int. corr.

ΔE<sub>exp</sub> = 2.306 ± 0.015 eV 95% c.l.

X-ray standard from pionic atoms [1]

Accuracy of X-ray energies limited by the pion mass: good standard for the few keV regime [1]

[1] D.F. Anagnostopoulos *et al.*, Phys. Rev. Lett. **91**, 240801 (2003).









## **PION MASS collaboration**



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Thankyoul